



4/8/2009

RELIABILITY MONITOR REPORT  
FOR

**TSMC 0.35 $\mu$ m Silicon Gate CMOS**

**MAXIM Integrated Products**

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Sunnyvale, CA 94086

This Report was prepared by  
Maxim Reliability Engineering

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1446EHJ+	MAX7033EUI+	MAX7034AUI+	MAX7044AKA+	MAX9257GTL+
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The calculated failure rate for devices using this process is:

**FAILURE RATE:**                      **MTTF (YRS): 6437**                      **FITS: 17.7**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2007 and 6/30/2008 .

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**Process Information:**

Process Description:                      TSMC 0.35µm Silicon Gate CMOS

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0742	MAX9257GTL+	135C	192 HRS	55	0	QGFZCQ001EQ
HIGH TEMP OP LIFE	0804	MAX7034AUI+	135C	500 HRS	48	0	QINZAQ003D#
<b>Total:</b>						<b>0</b>	

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**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0616	MAX7033EUI+	150C	1000 HRS	78	0	QPM0BQ002S#
STORAGE LIFE	0804	MAX7034AUI+	150C	1000 HRS	80	0	QINZAQ003D#
<b>Total:</b>						<b>0</b>	

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**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0804	MAX7034AUI+	-65C TO 150C	500 CYS	80	0	QINZAQ003D#
<b>Total:</b>						<b>0</b>	

**FAILURE RATE:**                      **MTTF (YRS): 6437**                      **FITS: 17.7**